


<b>Search Notes</b>  	<b>Application/Control No.</b>  10584134	<b>Applicant(s)/Patent Under Reexamination</b>  YOSHIDA, NAOHIRO
	<b>Examiner</b>  Hau V Phan	<b>Art Unit</b>  3618

SEARCHED			
Class	Subclass	Date	Examiner
180	65.3, 65.4, 65.2, 65.8, 65.6	3/1/2008	HP
903	903, 902, 908, 944	3/1/2008	HP
429	17, 19	3/1/2008	HP
701	22	3/1/2008	HP
318	727, 700	3/1/2008	HP
320	104, 126, 101	3/1/2008	HP

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
180	65.1-65.8	3/1/2008	HP